

<b>Notice of References Cited</b>	Application/Control No. 10/730,707	Applicant(s)/Patent Under Reexamination UMEBAYASHI ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,297,157	10-1981	Van Vliet, Raymond A.	156/164
*	B	US-3,629,039	12-1971	Frick, Richard H.	156/269
*	C	US-2002/0129888	09-2002	Otsubo et al.	156/161
*	D	US-2002/0148557	10-2002	Heller et al.	156/252
*	E	US-2001/0025165	09-2001	Shimoe, Nariaki	604/385.27
*	F	US-4,720,415	01-1988	Vander Wielen et al.	428/152
*	G	US-4,239,578	12-1980	Gore, Graves T.	156/361
*	H	US-6,554,815	04-2003	Umebayashi, Toyoshi	604/385.27
*	I	US-4,543,141	09-1985	Bradley et al.	156/164
*	J	US-4,849,049	07-1989	Colton, Douglas E.	156/291
*	K	US-5,100,398	03-1992	Leroy et al.	604/385.25
*	L	US-4,409,049	10-1983	Passafiume et al.	156/164
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

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